EAST Search History (Prior Art)

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	109	defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:48
S2	63	analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726". clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:49
S3	0	transient power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S4	51	power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 17:00
S5	40	fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S6	40	current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726". clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S7	37	potential AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51

S8	9	voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S9	9	current AND voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S10	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/22 09:34
S11	11	current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:56
S12	27	current AND voltage AND fault AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:57
S13	11	fault location AND ("713".clas. OR "726". clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S14	14	(fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23

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S15	5	(("IC" OR integrated circuit) | (semiconductor OR semi-conductor)) AND (fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:34
S16	189433	(ishida.in. | yamaguchi.in. | hashimoto.in.)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:35
S17	36	(ishida.in. | yamaguchi.in. | hashimoto.in.) AND fault AND defect$3 AND analysis AND ("IC" | integrated circuit | semi$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:36
S18	205	(("IC" OR integrated circuit) | (semiconductor OR semi-conductor)) AND (fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S19	698	(fault location | defect$3 signal$1) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S20	278	current AND voltage AND fault AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S21	77	current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:42

S22	8	signal$1 AND fault AND current AND voltage AND (fault location | defect$3 signal$1) AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
S23	8	signal$1 AND fault$1 AND current AND voltage AND (fault location | defect$3 signal$1) AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
S24	26	(ishida.in. | yamaguchi.in. | hashimoto.in.) AND fault AND defect$3 AND analysis AND ("IC" | integrated circuit) AND (semi$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:48
S25	66	(stor$3 | memory | medium | media) AND current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:59
S26	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 16:40
S27	64	transient AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:32

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S28	20	transient current AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S29	6	transient current AND time AND integral AND voltage AND current AND fault AND power supply AND analysis AND defect$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S30	13	transient current AND time AND integral AND voltage AND current AND (fault | defect$3) AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:11
S31	8	(CMOS | complementary metal oxide semiconductor) AND transient current AND time AND integral AND voltage AND current AND (fault | defect$3) AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:12
S32	8	(CMOS | complementary metal oxide semi$1conductor | complementary symmetry metal oxide semi$1conductor) AND transient current AND time AND integral AND voltage AND current AND (fault | defect$3) AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:12

S33	6	(CMOS | complementary metal oxide semi$1conductor | complementary symmetry metal oxide semi$1conductor) AND transient AND time AND (sum NEAR integral) AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:15
S34	6	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S35	6	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S36	7	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S37	256	transient AND time AND (sum | total | talley) AND integral AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17
S38	56	(CMOS | complementary metal oxide semi$1conductor | complementary symmetry metal oxide semi$1conductor) AND transient AND time AND (sum | total | talley) AND integral AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17

S39	10	(CMOS | complementary metal oxide semi$1conductor | complementary symmetry metal oxide semi$1conductor) AND transient AND time AND (sum | total | talley) AND (time NEAR integral) AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17
S40	10	(CMOS | complementary metal oxide semi$1conductor | complementary symmetry metal oxide semi$1conductor) AND transient AND tim$3 AND (sum | total | talley) AND (time NEAR integral) AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:18
S41	69	(CMOS | complementary metal oxide semi$1conductor | complementary symmetry metal oxide semi$1conductor) AND transient AND time AND integral AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 10:17
S42	58	(test pattern | test criteri$2) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 10:35
S43	85	(test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:06

S44	26	abnormal$3 AND (test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:07
S45	56	fault$3 AND (test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:08
S46	23	fault$3 AND abnormal$3 AND (test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:08
S47	23	fault$3 AND abnormal$3 AND (test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:13
S48	8	"5943346".pn. | "5505539".pn. | "5864566".pn. | "4646299".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:16
S49	2	"6717428".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 16:43

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S50	12	fault$3 AND abnormal$3 AND (test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:23
S51	33	fault$3 AND (test pattern | test criteri$2 | test set) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:24
S52	43	fault$3 AND (test NEAR (pattern | criteri$2 | set)) AND (point$1 | data set$1 | measurement$1) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:24
S53	14	(anomaly | abnormal$3) AND fault$3 AND (test NEAR (pattern | criteri$2 | set)) AND (point$1 | data set$1 | measurement$1) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:25
S54	47	fault$3 AND (test NEAR (pattern | criteri$2 | set | signature)) AND (point$1 | data set$1 | measurement$1) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:42

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S55	14	fault$3 AND abnormal$3 AND (test NEAR (pattern | criteri$2 | set | signature)) AND (points | data sets | measurements) AND transient AND current AND power supply AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:42
S56	0	fault$3 AND (abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND (analysis NEAR (points | data sets | measurements)) AND current NEAR (transient NEAR power supply) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:43
S57	0	fault$3 AND (abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND (analysis NEAR (points | data sets | measurements)) AND (transient NEAR power supply NEAr current) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:44
S58	0	fault$3 AND (abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND (analysis NEAR (points | data sets | measurements)) AND (transient NEAR power supply NEAR current) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:44
S59	0	(abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND (analysis NEAR (points | data sets | measurements)) AND (transient NEAR power supply NEAR current) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73". clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:44

S60	1	(abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND analysis AND (points | data sets | measurements) AND (transient NEAR power supply NEAR current) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:44
S61	1	(abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND (points | data sets | measurements) AND (transient NEAR power supply NEAR current) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:44
S62	2	(abnormal$3 | anomal$3) AND (test NEAR (pattern | criteri$2 | set | signature)) AND (points | data sets | measurements) AND (transient SAME power supply current) AND analy$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 14:45
S63	4	"6215324".pn. | "4654582".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/05 15:12
S64	4	"5943346".pn. | "5864566".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 10:40
S65	2	"5025344".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 10:42

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S66	1	("DUT" | device under test) AND ("DDT" | "DD" | "IDDT") AND (abnormal$3 | anomal$3) AND test$3 AND transient AND current AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380". clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 11:07
S67	22	("DUT" | device under test) AND (abnormal$3 | anomal$3) AND test$3 AND transient AND current AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 11:08
S68	22	("DUT" | device under test) AND (abnormal$3 | anomal$3) AND test$3 AND ((transient AND current) OR (transient$1current)) AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. | "324".clas. | "326".clas. | "714".clas. | "73".clas.) AND (@pd<"20000404" | @ad<"20000404" | @prad<"20000404" | @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 11:09
S69	2	"6169408".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 14:08
S70	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 14:32
S71	2	"6717428".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 14:37
S72	2	"5483170".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2010/01/06 15:47